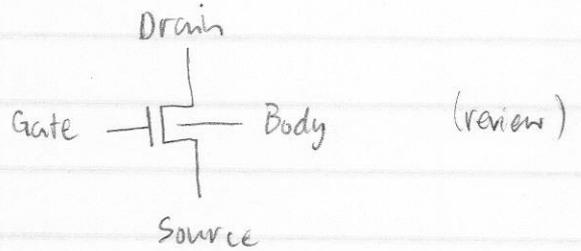


Chapter 3 - MOSFET R, C, latchup, and scaling

MOSFETs have 4 terminals



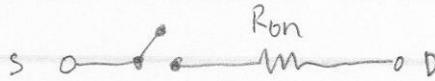
In common operation, we care most about:

input: gate voltage (V_G or V_{GS})

output: source-drain current (I_D)

MOSFET switch model:

If $V_{GS} < V_T$, $\rightarrow I_D \sim 0$ ($I_{LEAKAGE}$ only), where $V_T =$ "threshold" voltage

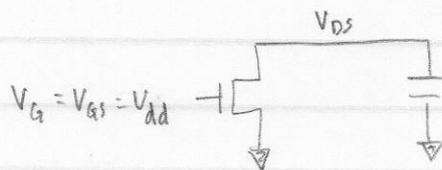


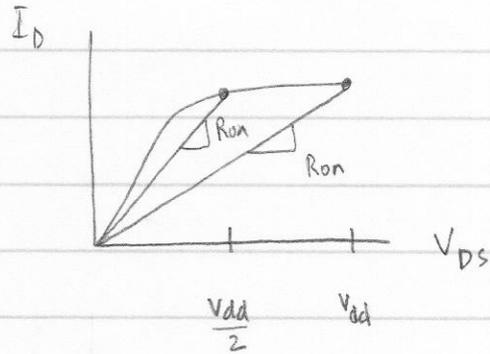
If $V_{GS} \geq V_T$, $\rightarrow I_D = \frac{V_{DS}}{R_{on}}$ (transistor "on")



I. MOSFET Resistance

But in a real transistor, R_{on} changes while switching





For speed purposes, we care about region where V_{DS} (output) goes from V_{DD} to $V_{DD}/2$.

Resistance R_{on} at these points is slope of lines through operating point and origin.

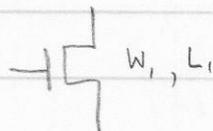
$$R_{on} = \frac{V_{DS}}{I_D}$$

switch-level

For our simulator for extracted layout (irisim) we will choose R_{on} by simulations so that delays closely match spice.

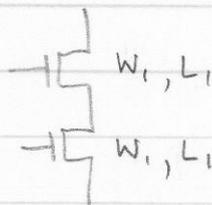
R_{on} is proportional to $\frac{\text{Transistor channel length}}{\text{Transistor channel width}} = \frac{L}{W} = \frac{1}{W/L}$

a)

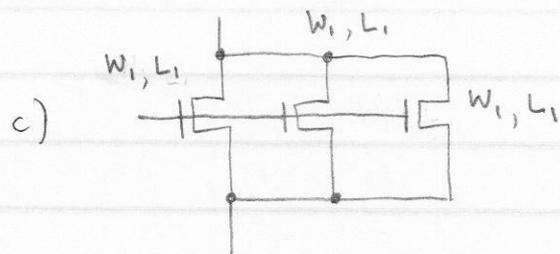


$$R_1 = K \frac{L_1}{W_1}$$

b)



$$R = K \frac{L_1 + L_1}{W_1} = 2 R_1$$



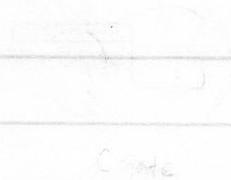
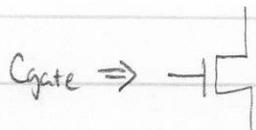
$$R = K \frac{L_1}{W_1 + W_1 + W_1} = \frac{R_1}{3}$$

Typical R_{on} values: (p. 106) For $0.25 \mu\text{m}$ with $W=L = 0.25 \mu\text{m}$

	V_{dd}			
	1V	1.5V	2V	2.5V
NMOS	35 $k\Omega$	19 $k\Omega$	15 $k\Omega$	13 $k\Omega$
PMOS	115	55	38	31

II. MOSFET Capacitance

A) Gate capacitance



Large component of load capacitance for circuits

Typical value for $0.25 \mu\text{m}$:

$$C_{ox} = 6 \text{ fF}/\mu\text{m}^2 \text{ for NMOS and PMOS}$$

i)



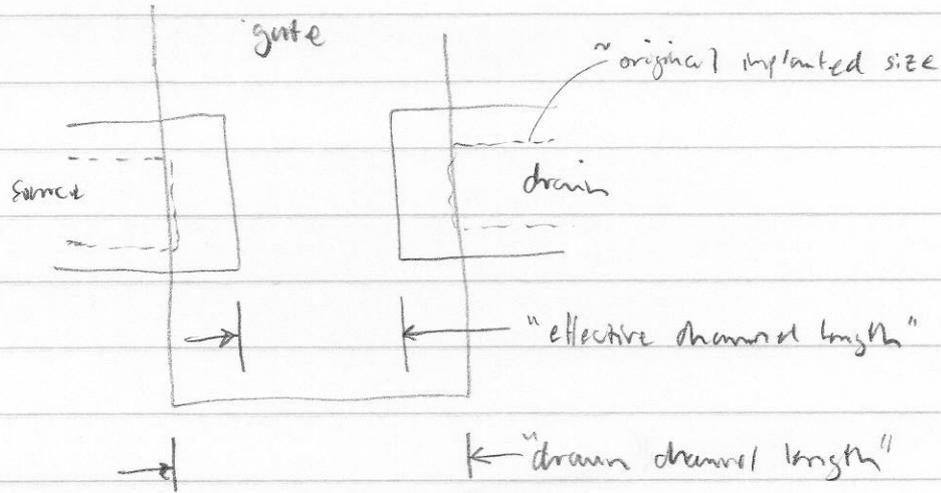
Bottom of gate to channel

ii)

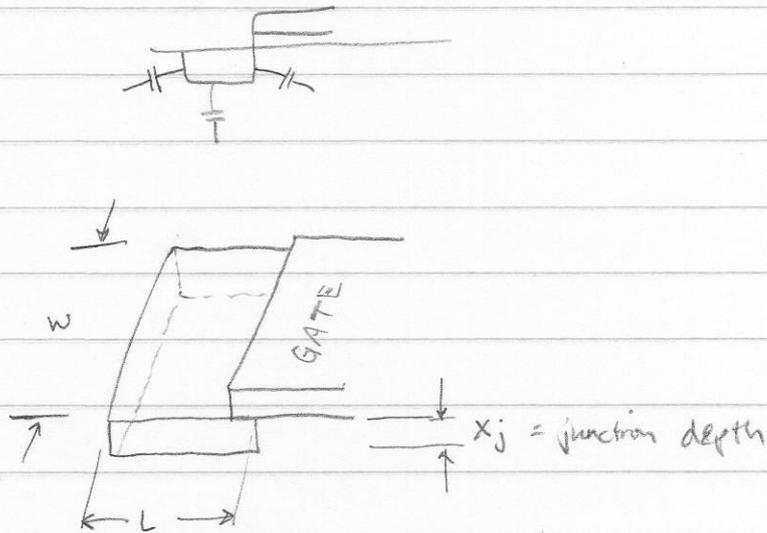


Sides of gate to source and drain

iii) Overlap capacitance: gate to source/drain:



B) Junction capacitances



- sidewall - area cap. of sides of junctions

$$C_{sw} = C'_{jsw} \cdot \text{sidewall area (3 sides only!)}$$

$$= C_{jsw} \cdot x_j \cdot \text{sidewall perimeter (" ")}$$

- bottom plate - area cap. of bottom of junctions

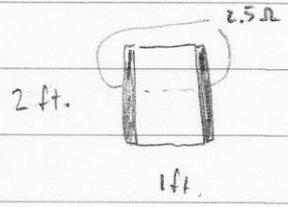
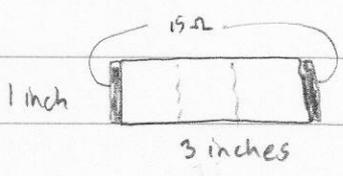
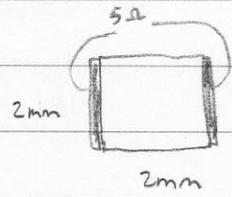
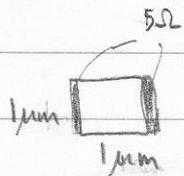
$$C_{\text{bottom}} = C_j^{\text{bottom}} \times \text{area}$$

III. Resistance of materials

Sheet resistance - units of $\Omega/\square = \Omega/\text{square}$.

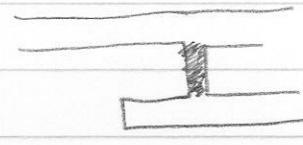
Resistivity and depth assumed constant

Ex. $5 \Omega/\square$ material



Typical values	0.18 μm CMOS
$7\Omega/\square$	N+
$8\Omega/\square$	P+
$8\Omega/\square$	poly
$2K\Omega/\square$	poly without silicide
$1K\Omega/\square$	hwell
$0.1\Omega/\square$	metal
$0.05\Omega/\square$	top metal (m6) (double-thick)

IV. Contact resistance



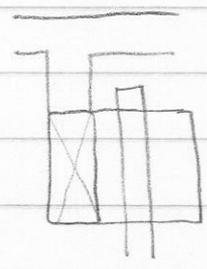
Aluminum or Tungsten

Typical 0.18 μm :

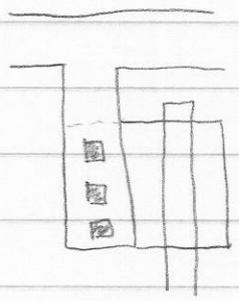
- 11 Ω N+ - M1
 - 11 Ω P+ - M1
 - 10 Ω poly - M1
 - 5 Ω M1 - M2
- } silicon to metal

for each contact

In magic,



In mask,



So use large contacts in a real chip if there is room or if there are high currents